

Form PTO-1449 U.S. Department of Commerce  
(REV. 2-82) Patent and Trademark Office

Atty. Docket No.  
036179/US/2-475387-30

Serial No.  
10/577,562

**INFORMATION DISCLOSURE STATEMENT  
BY APPLICANT**  
(Use several sheets if necessary)

Applicant(s)  
Seok-Hyun Yun

Filing Date  
April 27, 2006

Confirmation No.  
3634

**U.S. PATENT DOCUMENTS**

*Exam. Init.		Document No.							Date	Name	Class	Subclass	Filing Date if Appropriate
		6	3	4	1	0	3	6	January 22, 2002	Tearney et al. ○○○○○			
		6	3	9	6	9	4	1	May 28, 2002	Bacus, James W. et al. ○○○○○			
	200	5	0	1	8	2	0	1	January 27, 2005	De Boer, Johannes F. Et al ○○○○○			
		6	5	6	7	5	8	5	May 20, 2003	Martin et al ○○○○○			
		5	9	2	6	5	9	2	July 20, 1999	Martin et al. ○○○○○○○			
		7	2	6	7	4	9	4	September 11, 2007	Hongyu et al. ○○○○○○○			
		5	9	7	5	6	9	7	November 2, 1999	Podoleanu et al.			
		5	2	4	1	3	6	4	August 31, 1993	Kimura et al. ○○○○○○○ ○			
		5	9	1	0	8	3	9	June 8, 1999	Erskine et al ○○○○○○○ ○			
	200	7	0	7	0	4	9	6	March 29, 2007	Gweon et al. ○○○○○○○ ○			
		4	8	2	7	9	0	7	May 9, 1989	Tashiro et al. ○○○○○○○ ○			
		4	9	9	8	9	7	2	March 12, 1991	Chin et al. ○○○○○○○ ○			
		5	7	3	0	7	3	1	March 24, 1998	Mollenauer et al. ○○○○○○○ ○			
	200	3	1	2	0	1	3	7	June 26, 2003	Pawluczyk et al ≡			

Examiner

Date Considered

\* Examiner: Initial citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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	200	2	0	9	1	3	2	2	July 11, 2002	Chaiken et al. <del>¶¶</del>			
	2005	0	1	6	5	3	0	3	July 28, 2005	Kleen Martin et al. <del>¶¶¶</del>			
	200	2	0	5	2	5	4	7	May 2, 2002	Toida Masahiro <del>¶¶¶</del>			
	200	4	0	0	2	6	5	0	January 1, 2004	Mandrusov Evgenia et al. <del>¶¶¶</del>			
	200	3	0	8	2	1	0	5	May 1, 2003	Fischman, Alan et al. <del>¶¶¶</del>			
		5	3	0	4	1	7	3	April 19, 1994	Kittrell, Carter et al. <del>¶¶¶</del>			
		7	3	3	6	3	6	6	February 26, 2008	Choma et al.			
		7	0	1	9	8	3	8	March 28, 2006	Izatt et al.			
		6	3	7	4	1	2	8	April 16, 2002	Toida et al.			
		6	4	7	7	4	0	3	November 5, 2002	Eguchi et al.			
		5	5	5	5	0	8	7	September 10, 1996	Miyagawa et al. <del>¶¶¶¶</del>			
	200	5	0	5	7	7	5	6	March 17, 2005	Fang-Yen et al. <del>¶¶¶¶</del>			
	200	5	0	3	5	2	9	5	February 17, 2005	Bouma et al.			
	200	3	0	2	8	1	1	4	February 6, 2003	Casscells, III et al.			
	200	3	0	9	7	0	4	8	May 22, 2003	Ryan et al.			

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200	4	0	5	4	2	6	8	March 18, 2004	Esenaliev et al.			
200	4	0	7	7	9	4	9	April 22, 2004	Blotgett et al.			
200	4	0	7	2	2	0	0	April 15, 2004	Rigler et al.			
200	6	1	4	6	3	3	9	July 6, 2006	Fujita et al.			
200	4	2	6	3	8	4	3	December 30, 2004	Knopp et al.			

**FOREIGN PATENT DOCUMENT**

	Document No.							Date	Country	Class	SubClass	Translator	
												Yes	No
200	2	0	8	4	2	6	3	October 24, 2002	WIPO ΩΩΩΩΩ				
200	4	0	5	7	2	6	6	July 8, 2004	WIPO ΩΩΩΩΩ				
200	1	0	2	7	6	7	9	April 19, 2001	WIPO ΩΩΩΩΩΩ				
200	3	0	4	6	6	3	6	June 5, 2003	WIPO ΩΩΩΩΩΩ				
200	6	0	0	4	7	4	3	January 12, 2006	WIPOΩΩΩΩΩ ΩΩΩΩ				
	9	2	0	1	9	6	6	February 6, 1992	WIPO¥				
	6	0	7	3	4	0	5	April 25, 1985	Japan¥				
	5	5	0	9	4	1	7	November 22, 1993	Japan¥				
	2	7	3	8	3	4	3	August 30, 1995	France¥				
200	3	0	6	2	8	0	2	July 31, 2003	WIPO				

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	200	5	0	4	7	8	1	3	May 26, 2005	WIPO				
		2	2	9	8	0	5	4	August 21, 1996	Great Britain <del>YYY</del>				
	200	6	1	2	4	8	6	0	November 23, 2006	WIPO <del>YYY</del>				
		0	7	2	8	4	4	0	August 28, 1996	Europe				
	200	7	0	2	8	5	3	1	March 15, 2007	WIPO				
	199	8	0	4	8	8	4	6	November 5, 1998	WIPO				
	200	3	1	0	5	6	7	8	December 24, 2003	WIPO				
	200	6	0	3	9	0	9	1	April 13, 2006	WIPO				
	200	7	0	8	3	1	3	8	July 26, 2007	WIPO				
	200	6	0	5	9	1	0	9	June 8, 2006	WIPO				

~~QQQQ~~Reference cited in International Search Report and Written Opinion dated March 23, 2006 for International Application No. PCT/US2005/042408

~~QQQQ~~Reference cited in International Search Report and Written Opinion dated February 28, 2007 for International Application No. PCT/US2006/038277

~~QQQQ~~Reference cited in International Search Report and Written Opinion dated January 30, 2009 for International Application No. PCT/US2008/081834

~~QQQQ~~Reference cited in International Search Report and Written Opinion dated February 2, 2009 for International Application No. PCT/US2008/074863

~~QQQQ~~Reference cited in International Search Report and Written Opinion dated January 15, 2009 for International Application No. PCT/US2008/074863

~~YY~~Reference cited in Office Action dated February 17, 2009 for U.S. Patent application no. 11/211,483

~~YY~~Reference cited in Japanese Office Action dated December 2, 2008

~~YY~~Reference cited in International Search Report and Written Opinion dated February 24, 2009 for PCT/US2008/076447

~~YYY~~Reference cited in European Official Communication dated February 12, 2008 for EP 07718117.0

~~YYY~~Reference cited in International Search Report and Written Opinion dated June 10, 2009 for PCT/US2008/075456

## OTHER DOCUMENTS (including Author, Title Date, Pertinent Pages, Etc.)

Copy of International Search Report and Written Opinion dated December 20, 2004 for PCT/US04/10152

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			Copy of Notification Concerning Transmittal of Copy of International Preliminary Report on Patentability dated October 13, 2005 for PCT/US04/10152
			Copy of International Search Report and Written Opinion dated March 23, 2006 for PCT/US2005/042408
			Copy of International Preliminary Report on Patentability dated June 7, 2007 for PCT/US2005/042408
			Copy of International Search Report and Written Opinion dated February 28, 2007 for International Application No. PCT/US2006/038277 <del>XXXXXXXXXX</del>
			Copy of International Search Report and Written Opinion dated January 30, 2009 for International Application No. PCT/US2008/081834 <del>XXXXXXXXXX</del>
			Copy of International Search Report and Written Opinion dated February 2, 2009 for International Application No. PCT/US2008/071786 <del>XXXXXXXXXX</del>
			Bilenca A et al: "The Role of Amplitude and phase in Fluorescence Coherence Imaging: From Wide Field to Nanometer Depth Profiling", <i>Optics IEEE</i> , May 5, 2007 <del>XXXXXXXXXX</del>
			Inoue, Yusuke et al: "Variable Phase-Contrast Fluorescence Spectrometry for Fluorescently Strained Cells", <i>Applied Physics Letters</i> , September 18, 2006 <del>XXXXXXXXXX</del>
			Bernet, S et al: "Quantitative Imaging of Complex Samples by Spiral Phase Contrast Microscopy", <i>Optics Express</i> , May 9, 2006 <del>XXXXXXXXXX</del>
			Copy of International Search Report and Written Opinion dated January 15, 2009 for International Application No. PCT/US2008/074863
			Copy of Office Action dated February 17, 2009 for U.S. Patent application no. 11/211,483
			Copy of Notice of Reasons for Rejection mailed December 2, 2008 for Japanese patent application no. 2000-533782

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			Copy of International Search Report and Written Opinion dated February 24, 2009 for PCT/US2008/076447
			Copy of European Official Action dated December 2, 2008 for EP 07718117.0
			Barfuss et al (1989) "Modified Optical Frequency Domain Reflectometry with High spatial Resolution for Components of integrated optic Systems", Journal of Lightwave Technology, IEEE Vol 7., No. 1
			Yun et al., (2004) "Removing the Depth-Degeneracy in Optical Frequency Domain Imaging with Frequency Shifting", Optics Express, Vol. 12, No. 20
			Copy of International Search Report and Written Opinion dated June 10, 2009 for PCT/US08/075456
			Gelikono, V.M. et al. October 1, 2004 "Two-Wavelength Optical Coherence Tomography" Radio Physics and Quantum Electronics, Kluwer Academic Publishers-Consultants, Vol. 47, No. 10-1

4824-1162-7012/1

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